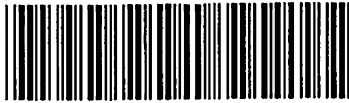


Search Notes

Application/Control No.

10/706,749

Examiner

Matthew G. Kayrish

Applicant(s)/Patent under
Reexamination

FURUYA ET AL.

Art Unit

2627

SEARCHED

Class	Subclass	Date	Examiner
720	675	4/6/2006	MK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR